

EAST - [921168a:1]

File View Edit Tools Window Help

Active

- L1: (79031) connect\$4 near9 gate near9 transistor
- L2: (8223) source same resistance same transistor same series
- L3: (2950) l1 and l2
- L4: (1096) source near9 resistance near9 transistor near9 series
- L5: (440) l1 and l4
- L6: (160919) power near9 (independen\$3 or differen\$3)
- L7: (77) l5 and l6
- L8: (71002) leakag\$3 near9 current
- L9: (16) l7 and l8

Failed

Saved

USPA ☒ Phrals

Default operator ☒ Highlight all hit terms rarely

17 and 18

	H	I	Document ID	Iss	Title	Current	Ci
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20030011247	20	Power supply device	307/125	
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20010002100	20	Battery polarity insensitive integrated circuit amplifier	320/165	25
3	<input type="checkbox"/>	<input type="checkbox"/>	US 6677214 B1	20	Semiconductor device and method of fabricating the same	438/365	25
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6462929 B2	20	Battery polarity insensitive integrated circuit amplifier	361/246	25
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6448852 B1	20	Battery polarity insensitive integrated circuit amplifier	330/251	25
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6225668 B1	20	Semiconductor device having a single crystal gate electrode	257/368	25
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6177706 B1	20	Field-effect thin-film transistor device	257/347	25
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6157252 A	20	Battery polarity insensitive integrated circuit amplifier	330/10	25
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6137120 A	20	Semiconductor device and method of fabricating the same	257/66	25
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6106734 A	20	Micromachine manufacture using gas beam crystallization	216/2	11
11	<input type="checkbox"/>	<input type="checkbox"/>	US 6025252 A	20	Semiconductor device and method of fabricating the same	438/509	13
12	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5745405 A	19	Process leakage evaluation and measurement method	365/154	36
13	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5738731 A	19	Photovoltaic device	136/249	13
14	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5490107 A	19	Nonvolatile semiconductor memory	365/185	36
15	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 4795917 A	19	Low power high voltage driver circuit	326/87	32
16	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 4591745 A	19	Power-on reset pulse generator	327/143	32

Hit Details HTML

Ready

HOME